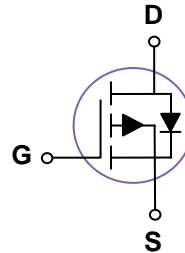
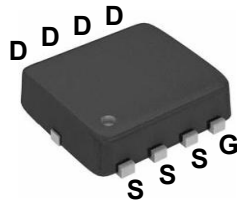


General Description

These P-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

Features

V_{DS}	-200V
I_D (at $V_{GS}=-10V$)	-5A
$R_{DS(ON)}$ (at $V_{GS}=-10V$)	1.4Ω(Typ)

PDFN3*3

Absolute Maximum Ratings $T_A=25^{\circ}C$ unless otherwise noted

Parameter	Symbol	Maximum	Units	
Drain-Source Voltage	V_{DS}	-200	V	
Gate-Source Voltage	V_{GS}	± 20	V	
Drain Current-Continuous	TC=25°C	I_D	-5	A
	TC=100°C	I_D	-4	A
Maximum Power Dissipation	P_D	35	W	
Drain Current – Pulsed ¹	I_{DM}	-20	A	
Single pulse avalanche energy ^{a5}	E_{AS}	-20	mJ	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	°C	

Thermal Characteristics

Parameter	Symbol	Typ	Max	Unit
Thermal Resistance junction-case	$R_{\theta JC}$		3.57	°C /W
Thermal Resistance junction-to-Ambient	$R_{\theta JA}$		62	°C /W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =-250μA	-200			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-200V, V _{GS} =0V			1	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V, V _{DS} =0V			100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =-250μA	-2.5	-3.5	-4.5	V
R _{DS(ON)}	Drain-Source On-State Resistance	V _{GS} =-10V, I _D =-2.5A		1.4	1.7	Ω
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{DS} =-25V, V _{GS} =0V, F=1.0MHz		480		pF
C _{OSS}	Output Capacitance			100		pF
C _{rSS}	Reverse Transfer Capacitance			30		pF
SWITCHING PARAMETERS						
t _{d(on)}	Turn-on Delay Time	V _{DD} =-160V, I _D =-2.5A V _{GS} =-10V R _G =9.1Ω		15		nS
t _r	Turn-on Rise Time			25		nS
t _{d(off)}	Turn-Off Delay Time			20		nS
t _f	Turn-Off Fall Time			15		nS
Q _g	Total Gate Charge	V _{DS} =-160V, I _D =-5A, V _{GS} =-10V		18		nC
Q _{gs}	Gate-Source Charge			9		nC
Q _{gd}	Gate-Drain Charge			8		nC
V _{SD}	Diode Forward Voltage	V _{GS} =0V, I _{SD} =-3A			1.2	V

Note:

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed , pulse width ≅ 300us , duty cycle ≅ 2%.
3. Essentially independent of operating temperature.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

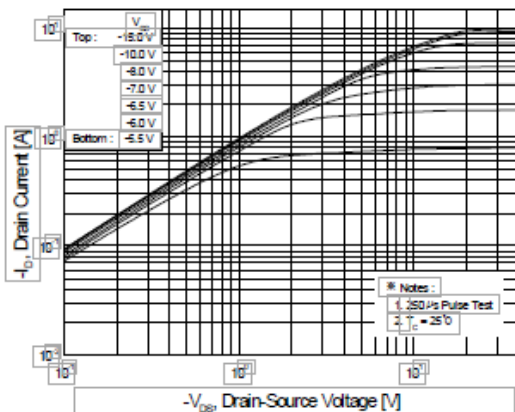


Figure 1. On-Region Characteristics

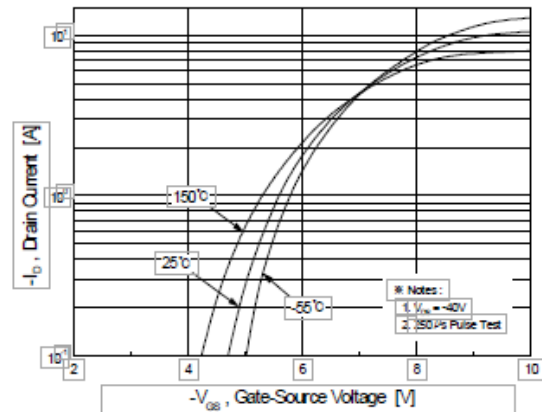


Figure 2. Transfer Characteristics

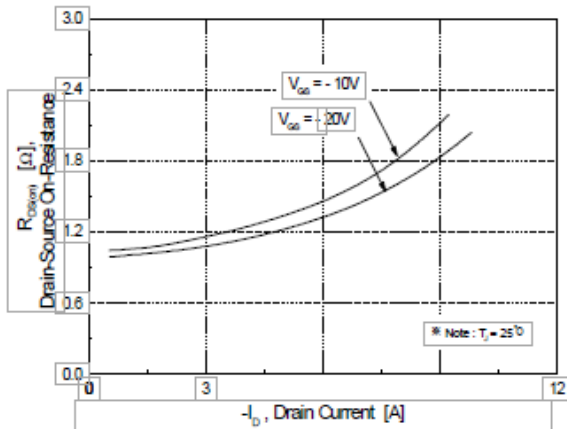


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

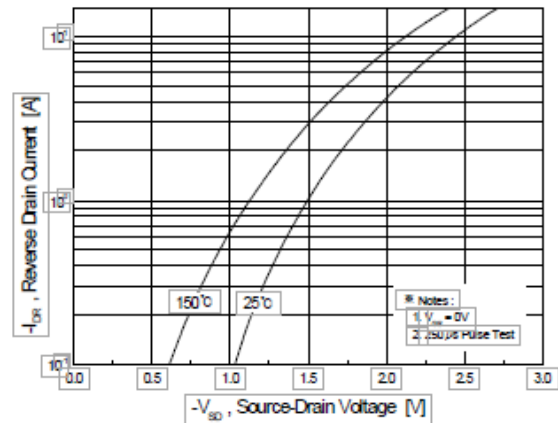


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

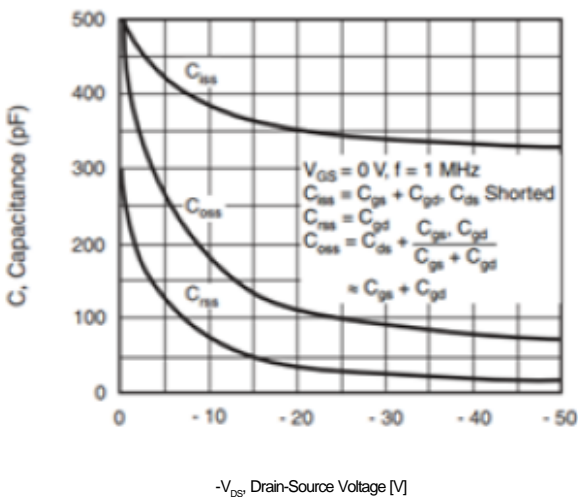


Figure 5. Capacitance Characteristics

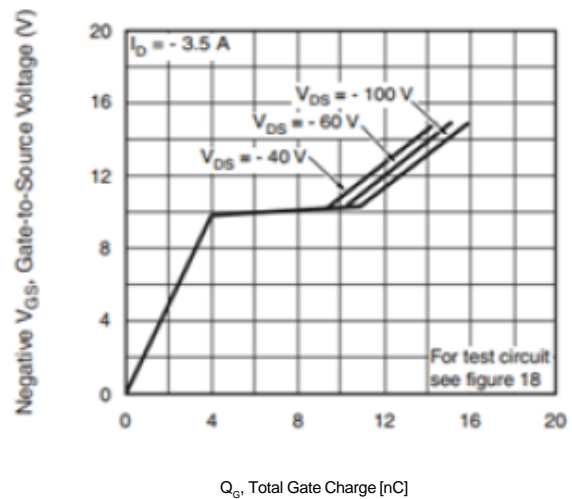


Figure 6. Gate Charge Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

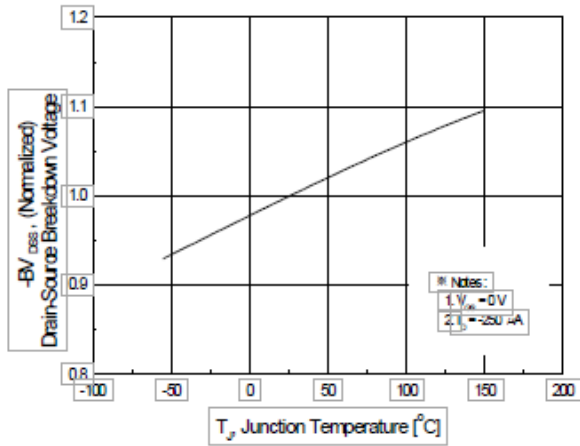


Figure 7. Breakdown Voltage Variation vs. Temperature

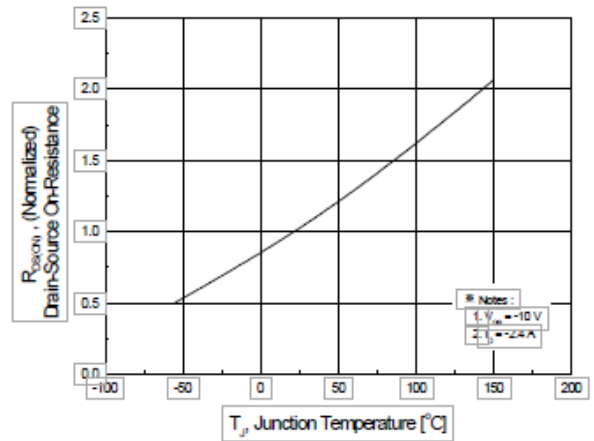


Figure 8. On-Resistance Variation vs. Temperature

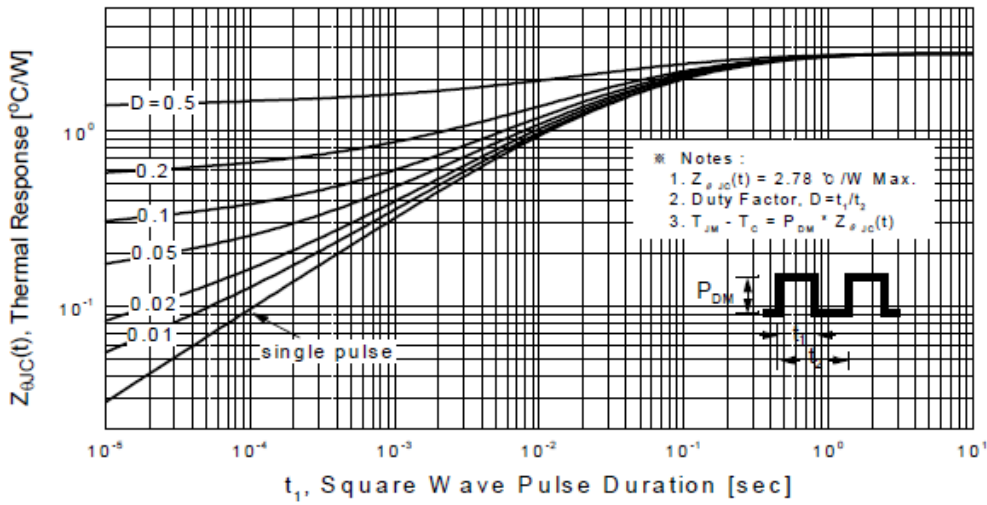
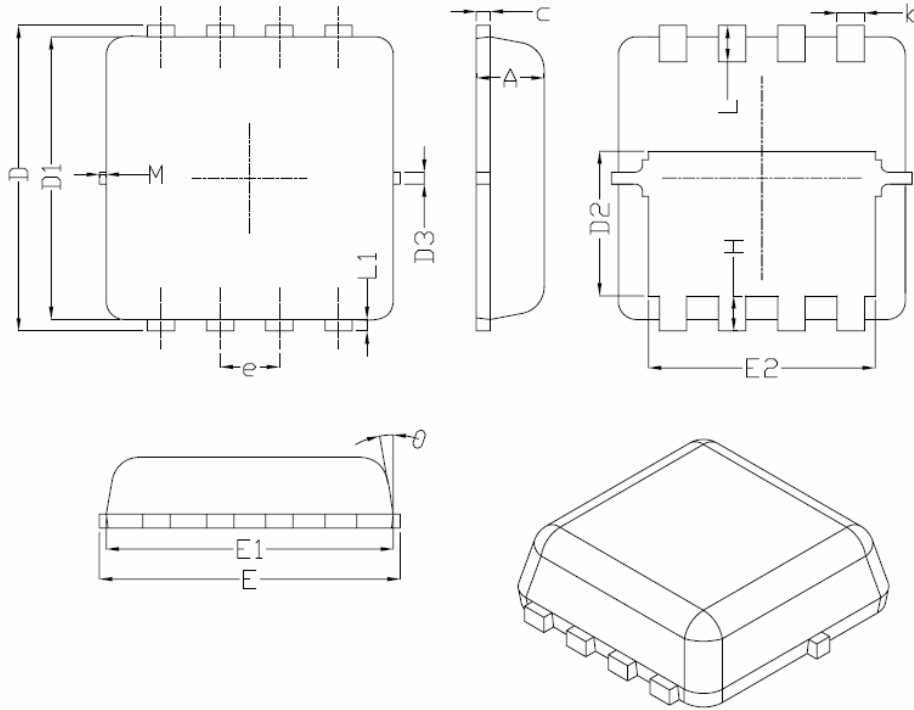


Figure 9. Normalized Maximum Transient Thermal Impedance

PDFN3x3 PACKAGE INFORMATION



Symbol	Dimensions In Millimeters		
	Min.	Nom.	Max.
A	0.70	0.75	0.80
b	0.25	0.30	0.35
c	0.10	0.15	0.25
D	3.25	3.35	3.45
D1	3.00	3.10	3.20
D2	1.48	1.58	1.68
D3	-	0.13	-
E	3.20	3.30	3.40
E1	3.00	3.15	3.20
E2	2.39	2.49	2.59
e	0.65BS		
H	0.30	0.39	0.50
L	0.30	0.40	0.50
L1	-	0.13	-
M	*	*	0.15
θ		10°	12°